

Search Notes

Application/Control No.

10/761,436

Examiner

Vivian Nelson

Applicant(s)/Patent under
Reexamination

NOVAK, W. THOMAS

Art Unit

2851

SEARCHED

Class	Subclass	Date	Examiner
355	53	6/30/2005	VHN
355	72,73	6/30/2005	VHN
355	75,76	6/30/2005	VHN
355	40,67	6/30/2005	VHN
350	399,400	7/12/2005	VHN
250	548	7/12/2005	VHN
356	400,401	7/12/2005	VHN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
355	53	2/13/2006	VHN
text PG-pub		2/14/2006	VHN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS search	6/24/2005	VHN
(height altitude level tilt) sensor and wafer (stage chuck); "surface profile" or "ideal height data"	6/24/2005	VHN
(measuring station) with (first second other); (measuring station) and (wafer stage, height sensor)	7/12/2005	VHN
Consulted with Hung Henry Nguyen	7/7/2005	VHN
Updated EAST search	2/14/2006	VHN